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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

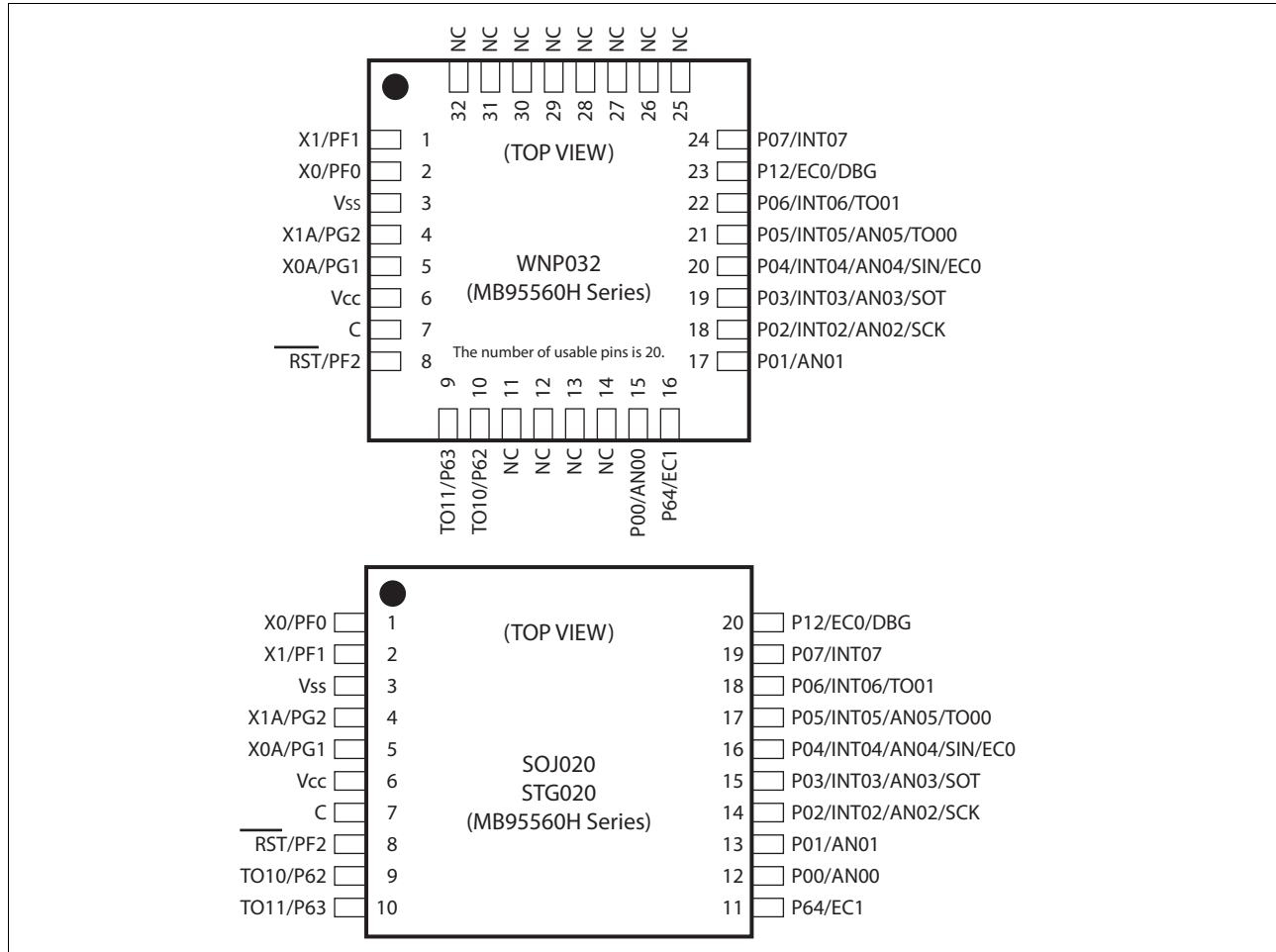
Product Status	Obsolete
Core Processor	F ² MC-8FX
Core Size	8-Bit
Speed	16MHz
Connectivity	LINbus, UART/USART
Peripherals	LVD, POR, PWM, WDT
Number of I/O	17
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	240 x 8
Voltage - Supply (Vcc/Vdd)	2.4V ~ 5.5V
Data Converters	A/D 6x8/10b
Oscillator Type	External
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	20-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	20-TSSOP
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb95f562kpft-g-sne2

Part number	MB95F582H	MB95F583H	MB95F584H	MB95F582K	MB95F583K	MB95F584K
Parameter						
Time-base timer	Interval time: 0.256 ms to 8.3 s (external clock frequency = 4 MHz)					
Hardware/ software watchdog timer	<ul style="list-style-type: none">Reset generation cycle Main oscillation clock at 10 MHz: 105 ms (Min)The sub-CR clock can be used as the source clock of the hardware watchdog timer.					
Wild register	It can be used to replace 3 bytes of data.					
LIN-UART	<ul style="list-style-type: none">A wide range of communication speed can be selected by a dedicated reload timer.It has a full duplex double buffer.Both clock synchronous serial data transfer and clock asynchronous serial data transfer are enabled.The LIN function can be used as a LIN master or a LIN slave.					
8/10-bit A/D converter	5 channels					
	8-bit or 10-bit resolution can be selected.					
8/16-bit composite timer	1 channel					
	<ul style="list-style-type: none">The timer can be configured as an "8-bit timer × 2 channels" or a "16-bit timer × 1 channel".It has the following functions: interval timer function, PWC function, PWM function and input capture function.Count clock: it can be selected from internal clocks (7 types) and external clocks.It can output square wave.					
External interrupt	6 channels					
	<ul style="list-style-type: none">Interrupt by edge detection (The rising edge, falling edge, or both edges can be selected.)It can be used to wake up the device from the standby mode.					
On-chip debug	<ul style="list-style-type: none">1-wire serial controlIt supports serial writing (asynchronous mode).					
Watch prescaler	Eight different time intervals can be selected.					
Flash memory	<ul style="list-style-type: none">It supports automatic programming (Embedded Algorithm), and program/erase/erase-suspend/erase-resume commands.It has a flag indicating the completion of the operation of Embedded Algorithm.Flash security feature for protecting the content of the Flash memory					
	Number of program/erase cycles		1000	10000	100000	
	Data retention time		20 years	10 years	5 years	
Standby mode	Sleep mode, stop mode, watch mode, time-base timer mode					
Package	WNP032 STB016 SO016					

3. Differences Among Products And Notes On Product Selection

- Current consumption
When using the on-chip debug function, take account of the current consumption of Flash memory program/erase.
For details of current consumption, see “Electrical Characteristics”.
- Package
For details of information on each package, see “Packages And Corresponding Products” and “Package Dimension”.
- Operating voltage
The operating voltage varies, depending on whether the on-chip debug function is used or not.
For details of the operating voltage, see “Electrical Characteristics”.
- On-chip debug function
The on-chip debug function requires that V_{CC} , V_{SS} and one serial wire be connected to an evaluation tool. For details of the connection method, refer to “CHAPTER 21 EXAMPLE OF SERIAL PROGRAMMING CONNECTION” in “New 8FX MB95560H/570H/580H Hardware Manual”.

4. Pin Assignment



Pin no.	Pin name	I/O circuit type*	Function
19	P03	D	General-purpose I/O port High-current pin
	INT03		External interrupt input pin
	AN03		A/D converter analog input pin
	SOT		LIN-UART data output pin
20	P04	D	General-purpose I/O port
	INT04		External interrupt input pin
	AN04		A/D converter analog input pin
	SIN		LIN-UART data input pin
	EC0		8/16-bit composite timer ch. 0 clock input pin
21	P05	D	General-purpose I/O port High-current pin
	INT05		External interrupt input pin
	AN05		A/D converter analog input pin
	TO00		8/16-bit composite timer ch. 0 output pin
22	P06	E	General-purpose I/O port High-current pin
	INT06		External interrupt input pin
	TO01		8/16-bit composite timer ch. 0 output pin
23	P12	F	General-purpose I/O port
	EC0		8/16-bit composite timer ch. 0 clock input pin
	DBG		DBG input pin
24	P07	E	General-purpose I/O port High-current pin
	INT07		External interrupt input pin
25	NC	—	It is an internally connected pin. Always leave it unconnected.
26			
27			
28			
29			
30			
31			
32			

*: For the I/O circuit types, see "I/O Circuit Type".

Pin no.	Pin name	I/O circuit type*	Function
20	P04	D	General-purpose I/O port
	INT04		External interrupt input pin
	AN04		A/D converter analog input pin
	SIN		LIN-UART data input pin
	EC0		8/16-bit composite timer ch. 0 clock input pin
21	P05	D	General-purpose I/O port High-current pin
	INT05		External interrupt input pin
	AN05		A/D converter analog input pin
	TO00		8/16-bit composite timer ch. 0 output pin
22	P06	E	General-purpose I/O port High-current pin
	INT06		External interrupt input pin
	TO01		8/16-bit composite timer ch. 0 output pin
23	P12	F	General-purpose I/O port
	EC0		8/16-bit composite timer ch. 0 clock input pin
	DBG		DBG input pin
24	P07	E	General-purpose I/O port High-current pin
	INT07		External interrupt input pin
25	NC	—	It is an internally connected pin. Always leave it unconnected.
26			
27			
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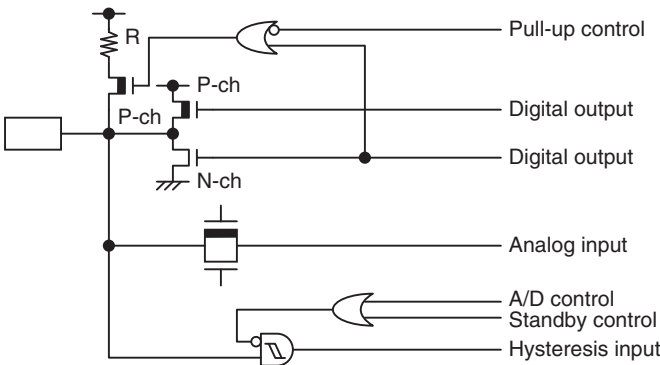
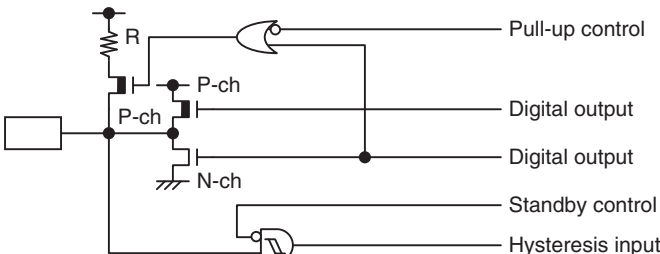
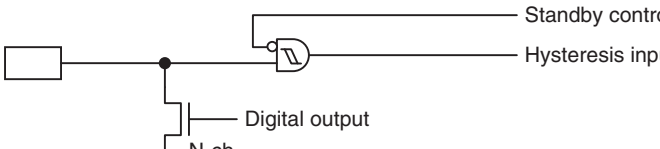
*: For the I/O circuit types, see "I/O Circuit Type".

9. Pin Functions (MB95580H Series, 16 pins)

Pin no.	Pin name	I/O circuit type*	Function
1	PF0	B	General-purpose I/O port
	X0		Main clock input oscillation pin
2	PF1	B	General-purpose I/O port
	X1		Main clock I/O oscillation pin
3	V _{ss}	—	Power supply pin (GND)
4	PG2	C	General-purpose I/O port
	X1A		Subclock I/O oscillation pin
5	PG1	C	General-purpose I/O port
	X0A		Subclock input oscillation pin
6	V _{cc}	—	Power supply pin
7	PF2	A	General-purpose I/O port
	$\overline{\text{RST}}$		Reset pin Dedicated reset pin on MB95F582H/F583H/F584H
8	C	—	Decoupling capacitor connection pin
9	P02	D	General-purpose I/O port High-current pin
	INT02		External interrupt input pin
	AN02		A/D converter analog input pin
	SCK		LIN-UART clock I/O pin
10	P01	D	General-purpose I/O port High-current pin
	AN01		A/D converter analog input pin
11	P03	D	General-purpose I/O port High-current pin
	INT03		External interrupt input pin
	AN03		A/D converter analog input pin
	SOT		LIN-UART data output pin
12	P04	D	General-purpose I/O port
	INT04		External interrupt input pin
	AN04		A/D converter analog input pin
	SIN		LIN-UART data input pin
	EC0		8/16-bit composite timer ch. 0 clock input pin

Pin no.	Pin name	I/O circuit type*	Function
13	P05	D	General-purpose I/O port High-current pin
	INT05		External interrupt input pin
	AN05		A/D converter analog input pin
	TO00		8/16-bit composite timer ch. 0 output pin
14	P06	E	General-purpose I/O port High-current pin
	INT06		External interrupt input pin
	TO01		8/16-bit composite timer ch. 0 output pin
15	P07	E	General-purpose I/O port High-current pin
	INT07		External interrupt input pin
16	P12	F	General-purpose I/O port
	EC0		8/16-bit composite timer ch. 0 clock input pin
	DBG		DBG input pin

*: For the I/O circuit types, see "I/O Circuit Type".

Type	Circuit	Remarks
D		<ul style="list-style-type: none"> • CMOS output • Hysteresis input • Pull-up control available • Analog input
E		<ul style="list-style-type: none"> • CMOS output • Hysteresis input • Pull-up control available
F		<ul style="list-style-type: none"> • N-ch open drain output • Hysteresis input

11. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

11.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

• Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

• Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

- (1) Maintain relative humidity in the working environment between 40% and 70%.
Use of an apparatus for ion generation may be needed to remove electricity.
- (2) Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- (3) Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 M Ω).
Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
- (4) Ground all fixtures and instruments, or protect with anti-static measures.
- (5) Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

11.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

(1) Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

(2) Discharge of Static Electricity

When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

(3) Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

(4) Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

(5) Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.

12. Notes On Device Handling

- Preventing latch-ups

When using the device, ensure that the voltage applied does not exceed the maximum voltage rating.

In a CMOS IC, if a voltage higher than V_{CC} or a voltage lower than V_{SS} is applied to an input/output pin that is neither a medium-withstand voltage pin nor a high-withstand voltage pin, or if a voltage out of the rating range of power supply voltage mentioned in "24.1 Absolute Maximum Ratings" of "Electrical Characteristics" is applied to the V_{CC} pin or the V_{SS} pin, a latch-up may occur.

When a latch-up occurs, power supply current increases significantly, which may cause a component to be thermally destroyed.

- Stabilizing supply voltage

Address	Register abbreviation	Register name	R/W	Initial value
0FEB _H	WDTH	Watchdog timer selection ID register (upper)	R	XXXXXXXX _B
0FEC _H	WDTL	Watchdog timer selection ID register (lower)	R	XXXXXXXX _B
0FED _H to 0FFF _H	—	(Disabled)	—	—

• R/W access symbols

R/W : Readable / Writable

R : Read only

• Initial value symbols

0 : The initial value of this bit is “0”.

1 : The initial value of this bit is “1”.

X : The initial value of this bit is undefined.

Note: Do not write to an address that is “(Disabled)”. If a “(Disabled)” address is read, an indeterminate value is returned.

Address	Register abbreviation	Register name	R/W	Initial value
006C _H	ADC1	8/10-bit A/D converter control register 1	R/W	00000000 _B
006D _H	ADC2	8/10-bit A/D converter control register 2	R/W	00000000 _B
006E _H	ADDH	8/10-bit A/D converter data register (upper)	R/W	00000000 _B
006F _H	ADDL	8/10-bit A/D converter data register (lower)	R/W	00000000 _B
0070 _H	—	(Disabled)	—	—
0071 _H	FSR2	Flash memory status register 2	R/W	00000000 _B
0072 _H	FSR	Flash memory status register	R/W	000X0000 _B
0073 _H	SWRE0	Flash memory sector write control register 0	R/W	00000000 _B
0074 _H	FSR3	Flash memory status register 3	R	000XXXXX _B
0075 _H	FSR4	Flash memory status register 4	R/W	00000000 _B
0076 _H	WREN	Wild register address compare enable register	R/W	00000000 _B
0077 _H	WROR	Wild register data test setting register	R/W	00000000 _B
0078 _H	—	Mirror of register bank pointer (RP) and direct bank pointer (DP)	—	—
0079 _H	ILR0	Interrupt level setting register 0	R/W	11111111 _B
007A _H	ILR1	Interrupt level setting register 1	R/W	11111111 _B
007B _H , 007C _H	—	(Disabled)	—	—
007D _H	ILR4	Interrupt level setting register 4	R/W	11111111 _B
007E _H	ILR5	Interrupt level setting register 5	R/W	11111111 _B
007F _H	—	(Disabled)	—	—
0F80 _H	WRARH0	Wild register address setting register (upper) ch. 0	R/W	00000000 _B
0F81 _H	WRARL0	Wild register address setting register (lower) ch. 0	R/W	00000000 _B
0F82 _H	WRDR0	Wild register data setting register ch. 0	R/W	00000000 _B
0F83 _H	WRARH1	Wild register address setting register (upper) ch. 1	R/W	00000000 _B
0F84 _H	WRARL1	Wild register address setting register (lower) ch. 1	R/W	00000000 _B
0F85 _H	WRDR1	Wild register data setting register ch. 1	R/W	00000000 _B
0F86 _H	WRARH2	Wild register address setting register (upper) ch. 2	R/W	00000000 _B
0F87 _H	WRARL2	Wild register address setting register (lower) ch. 2	R/W	00000000 _B
0F88 _H	WRDR2	Wild register data setting register ch. 2	R/W	00000000 _B
0F89 _H to 0F91 _H	—	(Disabled)	—	—
0F92 _H	T01CR0	8/16-bit composite timer 01 status control register 0	R/W	00000000 _B
0F93 _H	T00CR0	8/16-bit composite timer 00 status control register 0	R/W	00000000 _B
0F94 _H	T01DR	8/16-bit composite timer 01 data register	R/W	00000000 _B
0F95 _H	T00DR	8/16-bit composite timer 00 data register	R/W	00000000 _B
0F96 _H	TMCR0	8/16-bit composite timer 00/01 timer mode control register	R/W	00000000 _B
0F97 _H to 0FC2 _H	—	(Disabled)	—	—

Address	Register abbreviation	Register name	R/W	Initial value
0FC3 _H	AIDRL	A/D input disable register (lower)	R/W	00000000 _B
0FC4 _H to 0FE3 _H	—	(Disabled)	—	—
0FE4 _H	CRT _H	Main CR clock trimming register (upper)	R/W	000XXXXX _B
0FE5 _H	CRT _L	Main CR clock trimming register (lower)	R/W	000XXXXX _B
0FE6 _H	—	(Disabled)	—	—
0FE7 _H	CRT _{DA}	Main CR clock temperature dependent adjustment register	R/W	000XXXXX _B
0FE8 _H	SYSC	System configuration register	R/W	11000011 _B
0FE9 _H	CMCR	Clock monitoring control register	R/W	00000000 _B
0FEA _H	CMDR	Clock monitoring data register	R	00000000 _B
0FEB _H	WDTH	Watchdog timer selection ID register (upper)	R	XXXXXXXX _B
0FEC _H	WDTL	Watchdog timer selection ID register (lower)	R	XXXXXXXX _B
0FED _H to 0FFF _H	—	(Disabled)	—	—

• R/W access symbols

R/W : Readable / Writable

R : Read only

• Initial value symbols

0 : The initial value of this bit is “0”.

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23. Interrupt Source Table (MB95580H Series)

Interrupt source	Interrupt request number	Vector table address		Bit name of interrupt level setting register	Priority order of interrupt sources of the same level (occurring simultaneously)
		Upper	Lower		
External interrupt ch. 4	IRQ00	FFFA _H	FFFB _H	L00 [1:0]	<div>High</div> <div>↑</div> <div>↓</div> <div>Low</div>
External interrupt ch. 5	IRQ01	FFF8 _H	FFF9 _H	L01 [1:0]	
External interrupt ch. 2	IRQ02	FFF6 _H	FFF7 _H	L02 [1:0]	
External interrupt ch. 6					
External interrupt ch. 3	IRQ03	FFF4 _H	FFF5 _H	L03 [1:0]	
External interrupt ch. 7					
—	IRQ04	FFF2 _H	FFF3 _H	L04 [1:0]	
8/16-bit composite timer ch. 0 (lower)	IRQ05	FFF0 _H	FFF1 _H	L05 [1:0]	
8/16-bit composite timer ch. 0 (upper)	IRQ06	FFEE _H	FFEF _H	L06 [1:0]	
LIN-UART (reception)	IRQ07	FFEC _H	FFED _H	L07 [1:0]	
LIN-UART (transmission)	IRQ08	FFEA _H	FFEB _H	L08 [1:0]	
—	IRQ09	FFE8 _H	FFE9 _H	L09 [1:0]	
—	IRQ10	FFE6 _H	FFE7 _H	L10 [1:0]	
—	IRQ11	FFE4 _H	FFE5 _H	L11 [1:0]	
—	IRQ12	FFE2 _H	FFE3 _H	L12 [1:0]	
—	IRQ13	FFE0 _H	FFE1 _H	L13 [1:0]	
—	IRQ14	FFDE _H	FFDF _H	L14 [1:0]	
—	IRQ15	FFDC _H	FFDD _H	L15 [1:0]	
—	IRQ16	FFDA _H	FFDB _H	L16 [1:0]	
—	IRQ17	FFD8 _H	FFD9 _H	L17 [1:0]	
8/10-bit A/D converter	IRQ18	FFD6 _H	FFD7 _H	L18 [1:0]	
Time-base timer	IRQ19	FFD4 _H	FFD5 _H	L19 [1:0]	
Watch prescaler	IRQ20	FFD2 _H	FFD3 _H	L20 [1:0]	
—	IRQ21	FFD0 _H	FFD1 _H	L21 [1:0]	
—	IRQ22	FFCE _H	FFCF _H	L22 [1:0]	
Flash memory	IRQ23	FFCC _H	FFCD _H	L23 [1:0]	

24.3 DC Characteristics

($V_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{SS} = 0.0 \text{ V}$, $T_A = -40 \text{ }^{\circ}\text{C}$ to $+85 \text{ }^{\circ}\text{C}$)

Parameter	Symbol	Pin name	Condition	Value			Unit	Remarks
				Min	Typ	Max		
"H" level input voltage	V_{IH}	P04	—	$0.7 V_{CC}$	—	$V_{CC} + 0.3$	V	Hysteresis input
	V_{IHS}	P00* ³ to P03* ⁴ , P05 to P07* ⁴ , P12, P62 to P64* ³ , PF0* ⁴ , PF1* ⁴ , PG1* ⁴ , PG2* ⁴	—	$0.8 V_{CC}$	—	$V_{CC} + 0.3$	V	Hysteresis input
	V_{IHM}	PF2	—	$0.8 V_{CC}$	—	$V_{CC} + 0.3$	V	Hysteresis input
"L" level input voltage	V_{IL}	P04	—	$V_{SS} - 0.3$	—	$0.3 V_{CC}$	V	Hysteresis input
	V_{ILS}	P00* ³ to P03* ⁴ , P05 to P07* ⁴ , P12, P62 to P64* ³ , PF0* ⁴ , PF1* ⁴ , PG1* ⁴ , PG2* ⁴	—	$V_{SS} - 0.3$	—	$0.2 V_{CC}$	V	Hysteresis input
	V_{ILM}	PF2	—	$V_{SS} - 0.3$	—	$0.2 V_{CC}$	V	Hysteresis input
Open-drain output application voltage	V_D	P12, PF2	—	$V_{SS} - 0.3$	—	$V_{SS} + 5.5$	V	
"H" level output voltage	V_{OH1}	P04, PF0* ⁴ , PF1* ⁴ , PG1* ⁴ , PG2	$I_{OH} = -4 \text{ mA}$	$V_{CC} - 0.5$	—	—	V	
	V_{OH2}	P00* ³ to P03* ⁴ , P05 to P07* ⁴ , P62 to P64* ³	$I_{OH} = -8 \text{ mA}$	$V_{CC} - 0.5$	—	—	V	
"L" level output voltage	V_{OL1}	P04, P12, PF0 to PF2* ⁴ , PG1* ⁴ , PG2* ⁴	$I_{OL} = 4 \text{ mA}$	—	—	0.4	V	
	V_{OL2}	P00* ³ to P03* ⁴ , P05 to P07* ⁴ , P62 to P64* ³	$I_{OL} = 12 \text{ mA}$	—	—	0.4	V	
Input leak current (Hi-Z output leak current)	I_{LI}	All input pins	$0.0 \text{ V} < V_I < V_{CC}$	-5	—	+5	μA	When the internal pull-up resistor is disabled
Internal pull-up resistor	R_{PULL}	P00* ³ to P07* ⁴ , P62 to P64* ³ , PG1* ⁴ , PG2* ⁴	$V_I = 0 \text{ V}$	25	50	100	k Ω	When the internal pull-up resistor is enabled
Input capacitance	C_{IN}	Other than V_{CC} and V_{SS}	$f = 1 \text{ MHz}$	—	5	15	pF	

$(V_{CC} = 5.0 \text{ V} \pm 10\%, V_{SS} = 0.0 \text{ V}, T_A = -40 \text{ }^{\circ}\text{C} \text{ to } +85 \text{ }^{\circ}\text{C})$

Parameter	Symbol	Pin name	Condition	Value			Unit	Remarks
				Min	Typ ^{*1}	Max ^{*2}		
Power supply current ^{*5}	I _{LVD}	V _{CC}	Current consumption for the low-voltage detection circuit	—	3.6	6.6	μA	
	I _{CRH}		Current consumption for the main CR oscillator	—	220	280	μA	
	I _{CRL}		Current consumption for the sub-CR oscillator oscillating at 100 kHz	—	5.1	9.3	μA	
	I _{INSTBY}		Current consumption difference between normal standby mode and deep standby mode T _A = +25 °C	—	20	30	μA	

*1: V_{CC} = 5.0 V, T_A = + 25 °C

*2: V_{CC} = 5.5 V, T_A = + 85 °C (unless otherwise specified)

*3: P00, P62, P63 and P64 are only available on MB95F562H/F562K/F563H/F563K/F564H/F564K.

*4: P01, P02, P03, P07, PF0, PF1, PG1 and PG2 are only available on MB95F562H/F562K/F563H/F563K/F564H/F564K/F582H/F582K/F583H/F583K/F584H/F584K.

*5: • The power supply current is determined by the external clock. When the low-voltage detection option is selected, the power-supply current will be the sum of adding the current consumption of the low-voltage detection circuit (I_{LVD}) to one of the value from I_{CC} to I_{CH}. In addition, when both the low-voltage detection option and the CR oscillator are selected, the power supply current will be the sum of adding up the current consumption of the low-voltage detection circuit, the current consumption of the CR oscillators (I_{CRH}, I_{CRL}) and a specified value. In on-chip debug mode, the CR oscillator (I_{CRH}) and the low-voltage detection circuit are always enabled, and current consumption therefore increases accordingly.

- See “24.4 AC Characteristics: Clock Timing” for F_{CH} and F_{CL}.
- See “24.4 AC Characteristics: Source Clock / Machine Clock” for F_{MPL} and F_{MPL}.

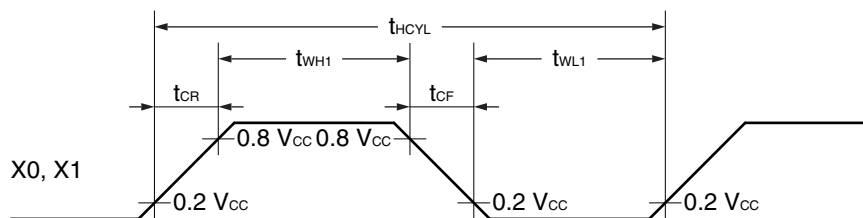
*6: In sub-CR clock mode, the power supply current value is the sum of adding I_{CRL} to I_{CCLS} or I_{CCT}. In addition, when the sub-CR clock mode is selected with F_{MPL} being 50 kHz, the current consumption increases accordingly.

$(V_{CC} = 2.4 \text{ V to } 5.5 \text{ V}, V_{SS} = 0.0 \text{ V}, T_A = -40^\circ\text{C to } +85^\circ\text{C})$

Parameter	Symbol	Pin name	Condition	Value			Unit	Remarks
				Min	Typ	Max		
Clock cycle time	t_{HCYL}	X0, X1	—	61.5	—	1000	ns	When the main oscillation circuit is used
		X0	X1: open	83.4	—	1000	ns	When an external clock is used
		X0, X1	*	30.8	—	1000	ns	When an external clock is used
	t_{LCYL}	X0A, X1A	—	—	30.5	—	μs	When the subclock is used
Input clock pulse width	t_{WH1}, t_{WL1}	X0	X1: open	33.4	—	—	ns	When an external clock is used, the duty ratio should range between 40% and 60%.
		X0, X1	*	12.4	—	—	ns	
	t_{WH2}, t_{WL2}	X0A	—	—	15.2	—	μs	
Input clock rising time and falling time	t_{CR}, t_{CF}	X0, X0A	X1: open	—	—	5	ns	When an external clock is used
		X0, X1, X0A, X1A	*	—	—	5	ns	
CR oscillation start time	t_{CRHWK}	—	—	—	—	50	μs	When the main CR clock is used
	t_{CRLWK}	—	—	—	—	30	μs	When the sub-CR clock is used

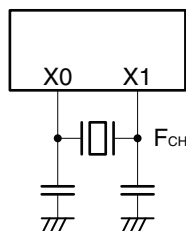
*: The external clock signal is input to X0 and the inverted external clock signal to X1.

- Input waveform generated when an external clock (main clock) is used

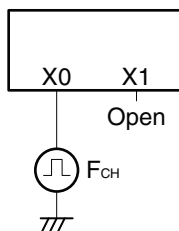


- Figure of main clock input port external connection

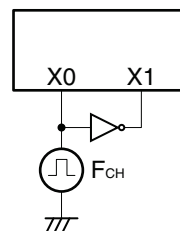
When a crystal oscillator or a ceramic oscillator is used



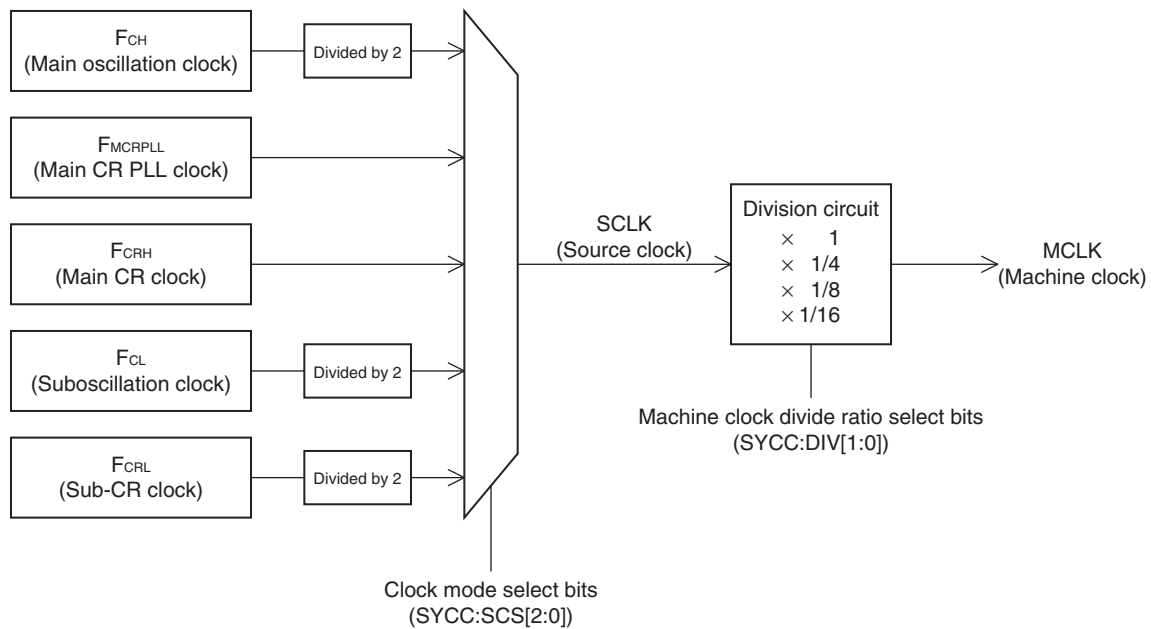
When an external clock is used (X1 is open)



When an external clock is used



• Schematic diagram of the clock generation block



Sampling is executed at the rising edge of the sampling clock*¹, and serial clock delay is enabled*².
 (ESCR register: SCES bit = 0, ECCR register: SCDE bit = 1)

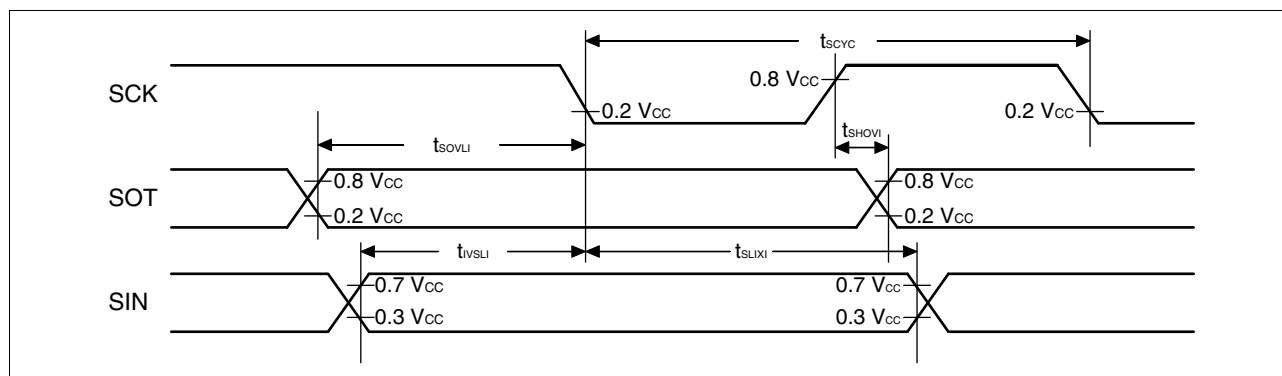
($V_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{SS} = 0.0 \text{ V}$, $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$)

Parameter	Symbol	Pin name	Condition	Value		Unit
				Min	Max	
Serial clock cycle time	t_{SCYC}	SCK	Internal clock operation output pin: $C_L = 80 \text{ pF} + 1 \text{ TTL}$	$5 t_{MCLK}^{*3}$	—	ns
SCK $\uparrow \rightarrow$ SOT delay time	t_{SHOVI}	SCK, SOT		-50	+50	ns
Valid SIN \rightarrow SCK \downarrow	t_{IVSLI}	SCK, SIN		$t_{MCLK}^{*3} + 80$	—	ns
SCK $\downarrow \rightarrow$ valid SIN hold time	t_{SLIXI}	SCK, SIN		0	—	ns
SOT \rightarrow SCK \downarrow delay time	t_{SOVLI}	SCK, SOT		$3 t_{MCLK}^{*3} - 70$	—	ns

*1: There is a function used to choose whether the sampling of reception data is performed at a rising edge or a falling edge of the serial clock.

*2: The serial clock delay function is a function that delays the output signal of the serial clock for half clock.

*3: See "Source Clock / Machine Clock" for t_{MCLK} .



Sampling is executed at the falling edge of the sampling clock*¹, and serial clock delay is enabled*².
 (ESCR register: SCES bit = 1, ECCR register: SCDE bit = 1)

($V_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{SS} = 0.0 \text{ V}$, $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$)

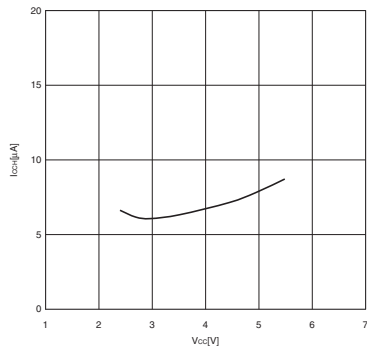
Parameter	Symbol	Pin name	Condition	Value		Unit
				Min	Max	
Serial clock cycle time	t_{SCYC}	SCK	Internal clock operating output pin: $C_L = 80 \text{ pF} + 1 \text{ TTL}$	$5 t_{MCLK}^{*3}$	—	ns
SCK $\downarrow \rightarrow$ SOT delay time	t_{SLOVI}	SCK, SOT		-50	+50	ns
Valid SIN \rightarrow SCK \uparrow	t_{IVSHI}	SCK, SIN		$t_{MCLK}^{*3} + 80$	—	ns
SCK $\uparrow \rightarrow$ valid SIN hold time	t_{SHIXI}	SCK, SIN		0	—	ns
SOT \rightarrow SCK \uparrow delay time	t_{SOVHI}	SCK, SOT		$3 t_{MCLK}^{*3} - 70$	—	ns

*1: There is a function used to choose whether the sampling of reception data is performed at a rising edge or a falling edge of the serial clock.

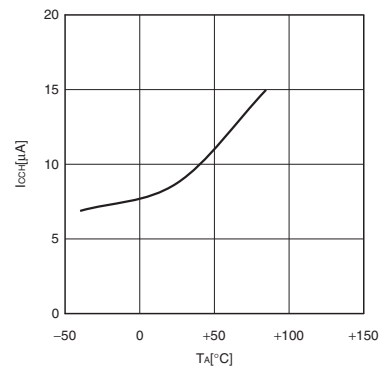
*2: The serial clock delay function is a function that delays the output signal of the serial clock for half clock.

*3: See "Source Clock / Machine Clock" for t_{MCLK} .

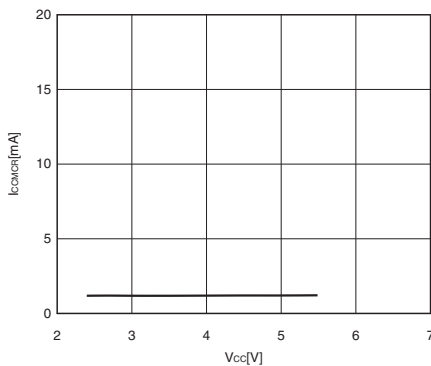
$I_{CCH} - V_{CC}$
 $T_A = +25^\circ\text{C}$, $F_{MPL} = (\text{stop})$
Substop mode with the external clock stopping



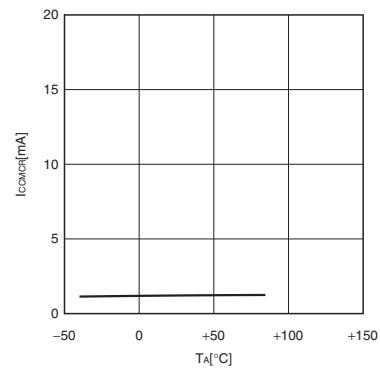
$I_{CCH} - T_A$
 $V_{CC} = 5.5\text{ V}$, $F_{MPL} = (\text{stop})$
Substop mode with the external clock stopping



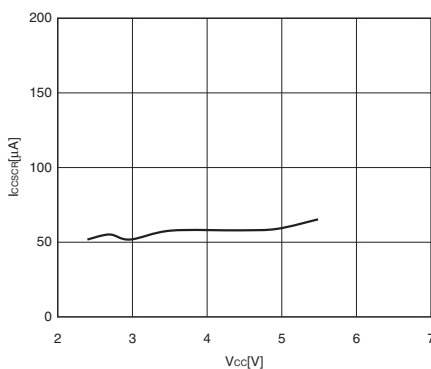
$I_{CCMCR} - V_{CC}$
 $T_A = +25^\circ\text{C}$, $F_{MP} = 4\text{ MHz}$ (no division)
Main clock mode with the main CR clock operating



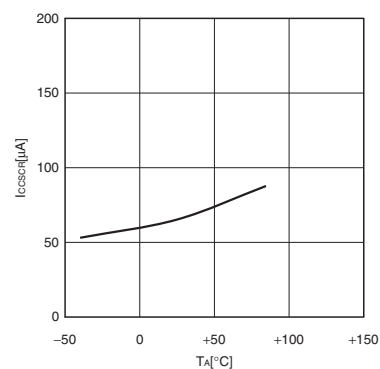
$I_{CCMCR} - T_A$
 $V_{CC} = 5.5\text{ V}$, $F_{MP} = 4\text{ MHz}$ (no division)
Main clock mode with the main CR clock operating



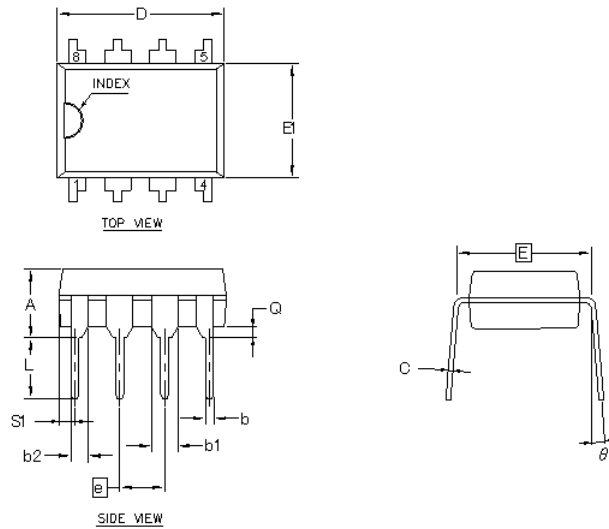
$I_{CCSCR} - V_{CC}$
 $T_A = +25^\circ\text{C}$, $F_{MPL} = 50\text{ kHz}$ (divided by 2)
Subclock mode with the sub-CR clock operating



$I_{CCSCR} - T_A$
 $V_{CC} = 5.5\text{ V}$, $F_{MPL} = 50\text{ kHz}$ (divided by 2)
Subclock mode with the sub-CR clock operating



Package Type	Package Code
DIP 8	PDA008



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	—	—	4.36
L	3.00	—	—
D	9.10	9.40	9.80
E	7.62 TYP		
E1	6.10	6.35	6.60
θ	—	—	15°
c	0.20	0.25	0.30
b	0.38	0.46	0.54
b1	—	1.52	1.82
b2	—	0.89	1.29
e	2.54 TYP		
S1	0.59	0.89	1.24
Q	0.50	—	—

NOTES

1. ALL DIMENSIONS ARE IN MILLIMETER.
2. JEDEC SPECIFICATION NO. REF : N/A

PACKAGE OUTLINE, 8 LEAD PDIP
 9-40528-35/12.98 MM PDA008 REV04

002-16909 **